



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): H. SHISHIDO, et al

FAX RECEIVED

Serial No.: 09/473,296

JAN 24 2000

Filed: December 28, 1999

GROUP 2700

For: METHOD AND EQUIPMENT FOR DETECTING PATTERN
DEFECT

Group: 2785

Examiner:

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

July 20, 2000

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

IN THE SPECIFICATION:

Please replace the original specification with the attached Substitute Specification.

BEST AVAILABLE COPY

IN THE CLAIMS:

Please amend the claims as follows:

Claim 1, line 2, before "laser" (first occurrence) insert
---a---; same line 2, delete "means";

line 4, delete "means";

line 14, delete "detecting an";

line 15, delete "image of said sample".